

# 校正報告書

校正暨量測實驗室-台北

Report Date : 2025/5/26

Report No. : ECR2519792		第1頁		共2頁	
申請者 Applicant	臺北醫學大學附設醫院				
儀器名稱 Equipment	-80℃超低溫冷凍櫃				
製造廠商 Manufacturer	PANASONIC	機型 Model	MDF-C8V1-P	序號 Serial No.	15100231
校正程序 Procedure used	GENP-EC-T014(V 1.7)	收件日期 Received Date	2025/5/20	校正日期 Calibration Date	2025/5/20
校驗者 Operator	耿志昌	溫度 ℃ Temperature	(20 ~ 21) ℃	相對濕度 % Relative Humidity	(57 ~ 59) %
顧客地址 遊校地址	11031臺北市信義區吳興街252號 11031臺北市信義區吳興街252號蔡萬才大樓			校正地點 Location	遊校

## 實驗室使用標準器 / SGS Standards

儀器名稱 Equipment	製造廠商 Manufacturer	機型 Model	標準器校正日期 Calibration Date
Multifunction Process Calibrator	FLUKE	725	2024/9/6
序號 Serial Number	追溯單位 Traceability	報告號碼 Report No.	標準器有效日期 Due Date
2759046	SGS(TAF 0143)	ECR2435125	2025/9/5

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- ◆ 有TAF認證標誌之報告表示符合全國認證基金會(TAF)認證範圍之校正項目證書；無TAF認證標誌之報告亦符合本實驗室標準校正作業程序及ISO/IEC 17025之規定。
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- ◆ The calibration report is only valid for the instrument mentioned above and has not been adjusted  
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- ◆ 校正程序名稱：烘箱(高低溫恒溫箱或冰箱等)校正作業程序書  
Calibration SOP for Oven (High and low temperature incubator or refrigerator etc.)
- ◆ Procedure used
- ALC 303

楊逸婷

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溫度部份：(比對校正)

器示值 (°C)	標準值 (°C)	器差值 (°C)
-84.0	-84.3	0.3

## 校正說明：

1. 器差值=器示值 - 標準值
2. 器示值係指送校正件所顯示或設定之值
3. 標準值係指工作標準件之輸出值或顯示值
4. 校正能力係以約95 %信賴水準,k=2之相對擴充不確定度表示
5. 擴充不確定度：0.5 °C
6. 上述擴充不確定度已包含校正件之不確定度評估結果

-- THE END --